

## Description

SEMICOA Corporation offers:

- Screening and processing per MIL-PRF-19500
- JAN level (2N2605J)
- JANTX level (2N2605JX)
- JANTXV level (2N2605JV)
- QCI to the applicable level
- 100% die visual inspection per MIL-STD-750 method 2072 for JANTXV
- Radiation testing (total dose) upon request

Please contact SEMICOA for special configurations  
www.**SEMICOA**.com or (714) 979-1900

## Applications

- Noise-level amplifier circuits
- Low power
- PNP silicon transistor



## Features

- Hermetically sealed TO-46 metal can
- Also available in chip configuration
- Chip geometry 0220
- Reference document: MIL-PRF-19500/354

## Benefits

- Qualification Levels: JAN, JANTX, and JANTXV
- Radiation testing available

Absolute Maximum Ratings		$T_C = 25^\circ\text{C}$ unless otherwise specified	
Parameter	Symbol	Rating	Unit
Collector-Emitter Voltage	$V_{CEO}$	60	Volts
Collector-Base Voltage	$V_{CBO}$	70	Volts
Emitter-Base Voltage	$V_{EBO}$	6	Volts
Collector Current, Continuous	$I_C$	30	mA
Power Dissipation, $T_A = 25^\circ\text{C}$ Derate linearly above $25^\circ\text{C}$	$P_T$	400 2.28	mW mW/ $^\circ\text{C}$
Thermal Resistance	$R_{\theta JA}$	437	$^\circ\text{C}/\text{W}$
Operating Junction Temperature Storage Temperature	$T_J$ $T_{STG}$	-65 to +200	$^\circ\text{C}$

### ELECTRICAL CHARACTERISTICS

 characteristics specified at  $T_A = 25^\circ\text{C}$ 

#### Off Characteristics

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Collector-Emitter Breakdown Voltage	$V_{(BR)CEO}$	$I_C = 10\text{ mA}$	60			Volts
Collector-Base Cutoff Current	$I_{CBO1}$ $I_{CBO2}$	$V_{CB} = 70\text{ Volts}$ $V_{CB} = 50\text{ Volts}$ $V_{CB} = \text{xx Volts}, T_A = \text{xxx}^\circ\text{C}$			10 10	$\mu\text{A}$ nA
Collector-Emitter Cutoff Current	$I_{CES}$	$V_{CE} = 50\text{ Volts}$			10	nA
Emitter-Base Cutoff Current	$I_{EBO1}$ $I_{EBO2}$	$V_{EB} = 6\text{ Volts}$ $V_{EB} = 5\text{ Volts}$			10 2	$\mu\text{A}$ nA

#### On Characteristics

 Pulse Test: Pulse Width = 300  $\mu\text{s}$ , Duty Cycle  $\leq 2.0\%$ 

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
DC Current Gain	$h_{FE1}$ $h_{FE2}$ $h_{FE3}$ $h_{FE4}$	$I_C = 10\ \mu\text{A}, V_{CE} = 5\text{ Volts}$ $I_C = 500\ \mu\text{A}, V_{CE} = 5\text{ Volts}$ $I_C = 10\text{ mA}, V_{CE} = 5\text{ Volts}$ $I_C = 10\ \mu\text{A}, V_{CE} = 5\text{ Volts}$ $T_A = -55^\circ\text{C}$	100 150 100 30		300 450 400	
Base-Emitter Saturation Voltage	$V_{BEsat1}$	$I_C = 10\text{ mA}, I_B = 500\ \mu\text{A}$	0.7		0.9	Volts
Collector-Emitter Saturation Voltage	$V_{CEsat1}$	$I_C = 10\text{ mA}, I_B = 500\ \mu\text{A}$			0.3	Volts

#### Dynamic Characteristics

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Magnitude – Common Emitter, Short Circuit Forward Current Transfer Ratio	$ h_{FE} $	$V_{CE} = 5\text{ Volts}, I_C = 0.5\text{ mA}, f = 30\text{ MHz}$	1		8	
Small Signal Short Circuit Forward Current Transfer Ratio	$h_{FE}$	$V_{CE} = 5\text{ Volts}, I_C = 1\text{ mA}, f = 1\text{ kHz}$	150		450	
Open Circuit Output Capacitance	$C_{OBO}$	$V_{CB} = 5\text{ Volts}, I_E = 0\text{ mA}, 100\text{ kHz} < f < 1\text{ MHz}$			6	pF
Noise Figure	$NF_1$ $NF_2$ $NF_3$	$V_{CE} = 5\text{ Volts}, I_C = 10\ \mu\text{A}, R_g = 10\text{ k}\Omega$ $f = 100\text{ Hz}$ $f = 1\text{ kHz}$ $f = 10\text{ kHz}$			5 3 3	dB
Short Circuit Input Impedance	$h_{ie}$	$V_{CB} = 5\text{V}, I_C = 1\text{mA}, f = 1\text{kHz}$	2		20	K $\Omega$
Open Circuit Output Admittance	$h_{oe}$	$V_{CB} = 5\text{V}, I_C = 1\text{mA}, f = 1\text{kHz}$			60	$\mu\text{mhos}$
Open Circuit reverse Voltage Transfer Ratio	$h_{re}$	$V_{CB} = 5\text{V}, I_C = 1\text{mA}, f = 1\text{kHz}$			$10 \times 10^{-4}$	